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PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B-R5-SOT23B-2YW
Type: Semiconductor Device Tester
S.N.: 13264
Date: February 19, 2015

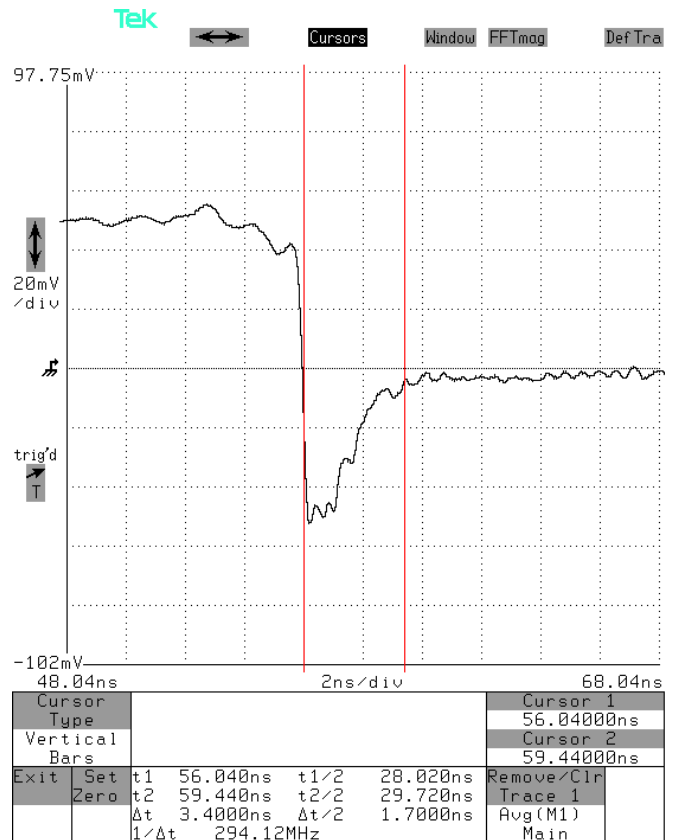
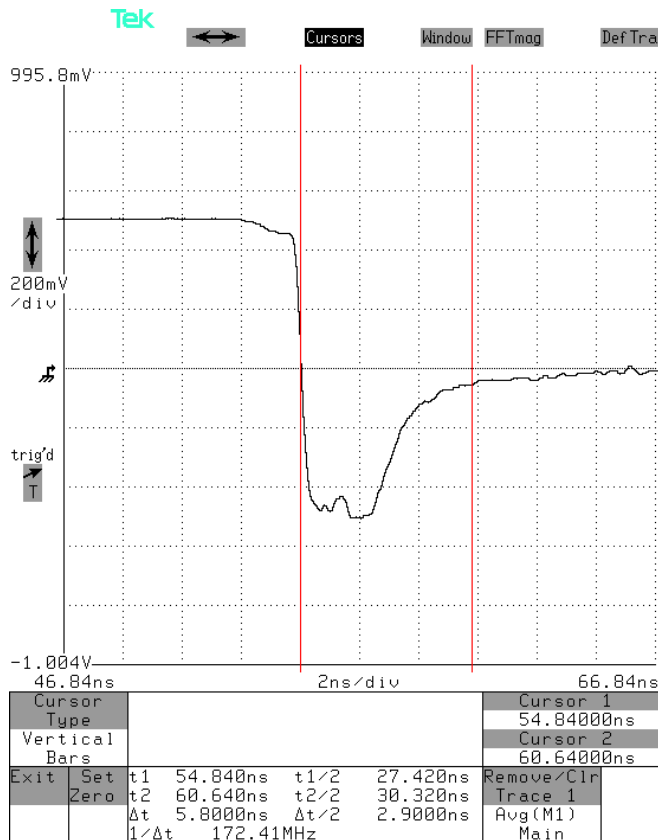
Output Amplitude: to +100 mA, -100 mA
Pulse Width (FWHM): 200 ns
Switching Time,
+ to -, 10%-90%: ≤ 300 ps (at mainframe)
PRF: 1 - 10 kHz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

With a Fairchild MMBD4148CC installed in the AVX-CA-SOT23B test jig, with pin 1 = anode, pin 3 = cathode, pin 2 = unused. 40 mA/div, 2 ns/div.

With a Fairchild MMBD4148CC installed in the AVX-CA-SOT23B test jig, with pin 2 = anode, pin 3 = cathode, pin 1 = unused. 4 mA/div, 2 ns/div.



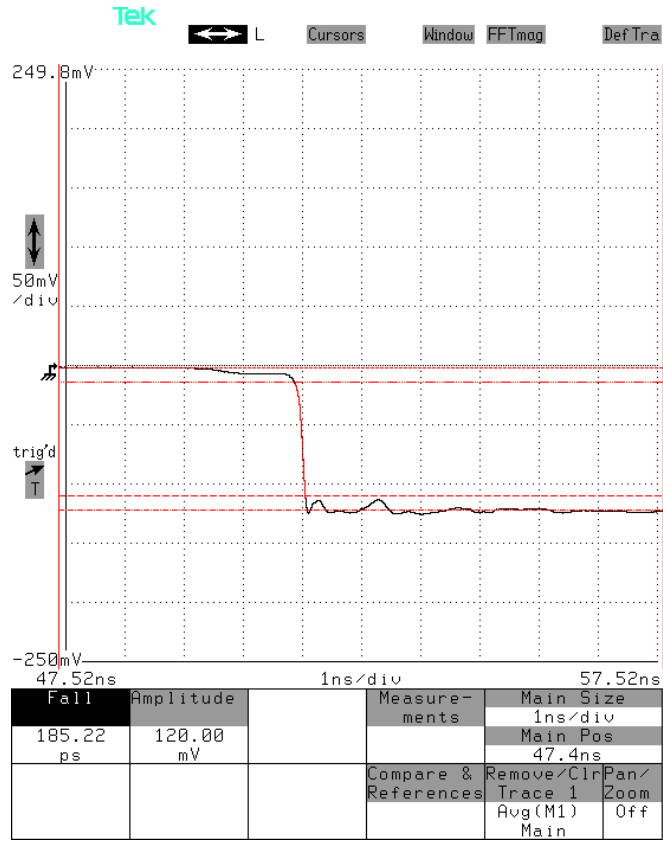
I_F = +100 mA, I_R = - 100 mA, I_{RR} = - 10 mA,

I_F = +10 mA, I_R = - 10 mA, I_{RR} = - 1 mA,

Measured t_{RR} = 5.8 ns.

Measured t_{RR} = 3.4 ns.

Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 1 ns/div):



Shows a 10%-90% transition time of 185 ps.